| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--------------|--|---------------------|---------|------------------|
| L1 | 594 | 702/118 | US-PGPUB; USPAT; EPO; DERWENT | OR . | ON | 2005/09/21 09:23 |
| L2 | 1714 | 702/183 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:23 |
| L3 | 674 | 702/184 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:23 |
| L4 | 892 | 702/185 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON . | 2005/09/21 09:24 |
| L5 | 228 | 714/715 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:24 |
| L6 | 1781 | 714/718 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:24 |
| L7 | 257 | 714/721 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:24 |
| L8 | 306 | 714/732 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:25 |
| L9 | 367 | 714/735 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:25 |
| L10 | 1060 | 714/738 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:25 |
| L11 | 528 | 438/10 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:26 |
| L12 | 339 | 438/11 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:26 |

| L13 | 185 | 438/12 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:26 |
|-----|------|---|--|----|----|------------------|
| L14 | 1768 | 438/17 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:26 |
| L15 | 19 | 365/189.9 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:26 |
| L16 | 6219 | 365/201 | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:27 |
| L17 | 64 | (cell with (memory DRAM)) and (analyze analyzing analyse) and voltage and node and (failure fail) and (test testing) and pattern.clm. | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:30 |
| L18 | 89 | (cell with (memory DRAM)) and (analyze analyzing analyse) and voltage and node and (failure fail) and ((test adj pattern) or (testing adj pattern)) and first and second | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:31 |
| L19 | 2 | (cell with (memory DRAM)) and (analyze analyzing analyse) and voltage and node and ((failure adj signature) or (fail adj signature)) and ((test adj pattern) or (testing adj pattern)) and first and second | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:36 |
| L20 | 1 | (cell with (memory DRAM)) and (analyze analyzing analyse) and voltage and node and ((failure adj signature) or (fail adj signature)) and ((test adj pattern) or (testing adj pattern)) and first and second. clm. | US-PGPUB; USPAT; EPO; DERWENT | OR | ON | 2005/09/21 09:36 |